


<b>Search Notes</b>  	<b>Application/Control No.</b>  10045625	<b>Applicant(s)/Patent Under Reexamination</b>  SHIN ET AL.
	<b>Examiner</b>  Steven Nguyen	<b>Art Unit</b>  2419

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
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See East text search	4/21/2009	ST
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INTERFERENCE SEARCH			
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	See east text search	2/3/2010	st

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